# **Specifications**

| Drawing No.  | USY1M-H1-16575-00 | 1 /10 |
|--------------|-------------------|-------|
| Issued Date. | Jun,3,2016        |       |

# Messrs: Digi-Key

# Note: Part Number will be revised in case of specification change.

| Product Type                           | Quartz Crystal       |  |
|--|----------------------|--|
| Series                                 | CX2016DB             |  |
| Frequency                              | 48000kHz             |  |
| Customer Part Number                   | -                    |  |
| Customer Specification Number          | -                    |  |
| KYOCERA Part Number                    | CX2016DB48000E0DLFA1 |  |
| Remarks Pb-Free, RoHS Compliant, MSL 1 |                      |  |

# **Customer Approval**

| Approval Signature | Approved Date    |  |
|--------------------|------------------|--|
|                    | Department       |  |
|                    | Person in charge |  |

# Seller

KYOCERA Crystal Device Corporation (Sales Division) 6 Takeda Tobadono-cho, Fushimi-ku, Kyoto 612-8501 Japan TEL. No. 075-604-3500 FAX. No. 075-604-3501

# Manufacturer

KYOCERA Crystal Device Corporation Crystal Units Division 5850, Higashine-Koh, Higashine-Shi, Yamagata 999-3701 Japan TEL. No. 0237-43-5611 FAX. No. 0237-43-5615

| Design Department   | Quality Assurance | Approved by | Checked by | Issued by |
|---|-------------------|-------------|------------|-----------|
| KYOCERA Crystal Device Corporation<br>Crystal Unit Design Engineering Section<br>Crystal Units Division | S.Itoh            | T.Soda      | A.Muraoka  | Y.Nozaki  |

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# **Revision History**

| Rev.No. | Description of revise | Date       | Approved by | Checked by | Issued by |
|---------|-----------------------|------------|-------------|------------|-----------|
| 00      | First Edition         | Jun,3,2016 | T.Soda      | A.Muraoka  | Y.Nozaki  |
|         |                       |            |             |            |           |
|         |                       |            |             |            |           |

# **1. APPLICATION**

The purpose of this document is applied to CX2016DB quartz crystal.

# 2. KYOCERA PART NUMBER

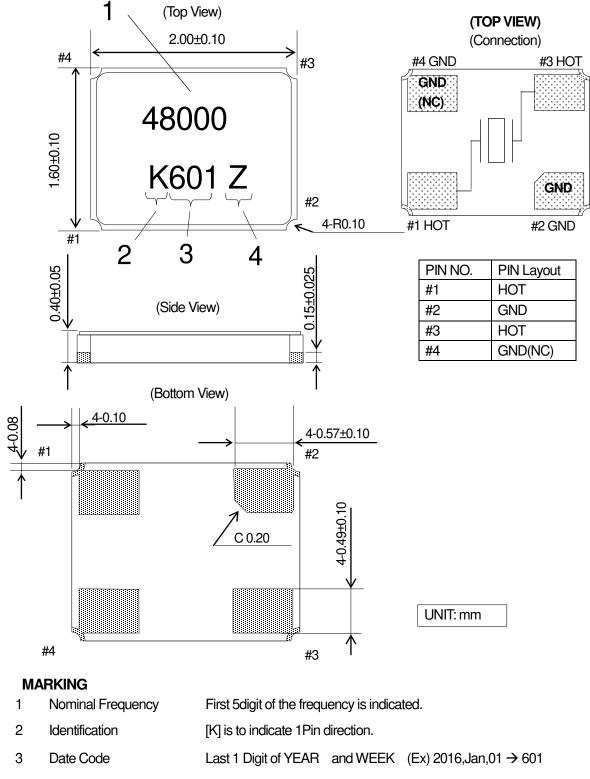
CX2016DB48000E0DLFA1

# **3. RATINGS**

| Items                       | SYMB. | Rating  | Unit   | Remarks |
|-----------------------------|-------|---------|--------|---------|
| Operating Temperature range | Topr  | -30~+85 | deg. C |         |
| Storage Temperature range   | Tstg  | -40~+85 | deg. C |         |

# 4. CHARACTERISTICS 4-1 ELECTRICAL CHARACTERISTICS

| Items                                    |                  | Electrical Specification |        |       |      | Test Condition                         | Remarks    |
|--|------------------|--------------------------|--------|-------|------|--|------------|
|  | SYMB.            | Min                      | Тур.   | Max   | Unit |  | Tiemaiks   |
| Mode of Vibration                        |                  | F                        | undame | ntal  |      |  |            |
| Nominal Frequency                        | F0               |                          | 48     |       | MHz  |  |            |
| Nominal Temperature                      | T <sub>NOM</sub> |                          | +25    |       | °C   |  |            |
| Load Capacitance                         | CL               |                          | 11.1   |       | pF   | IEC 60444-8 STD<br>(Pi circuit 41901A) |            |
| Frequency Tolerance                      | df/F             | -8.0                     |        | +8.0  |      | Network Analyzer<br>E5100A             |            |
| Frequency Temperature<br>characteristics | df/F             | -10.0                    |        | +10.0 | PPM  | -30~+85°C                              |            |
| Frequency Ageing Rate                    |                  | -2.0                     |        | +2.0  |      | 5 years                                | At +25±3°C |
| Equivalent Series<br>Resistance          | ESR              |                          |        | 22    | Ω    |  |            |
| Spurious mode series resistance          |                  | 1100                     |        |       | Ω    |  | ±700kHz    |
| Drive Level                              | Pd               | 10                       |        | 100   | μW   |  |            |
| Insulation Resistance                    | IR               | 500                      |        |       | MΩ   | 100V(DC)                               |            |
| Shunt Capacitance                        | C <sub>0</sub>   | 0.64                     | 0.84   | 1.04  | pF   | IEC 60444-8 STD<br>(Pi circuit 41901A) |            |
| Motional Capacitance                     | C <sub>1</sub>   | 2.16                     | 3.16   | 4.16  | fF   |  |            |
| Motional Inductance                      | L <sub>1</sub>   | 1.00                     | 3.49   | 4.00  | mH   |  |            |

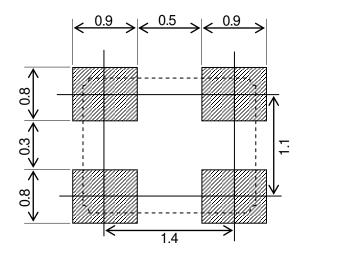


# 5. APPEARANCES, PHYSICAL DIMENSION OUTLINE DIMENSION (not to scale)

- 4 Manufacturing Location Y→Japan (Yamagata )
  - Z→Japan (Shiga Yohkaichi ) T→Thailand

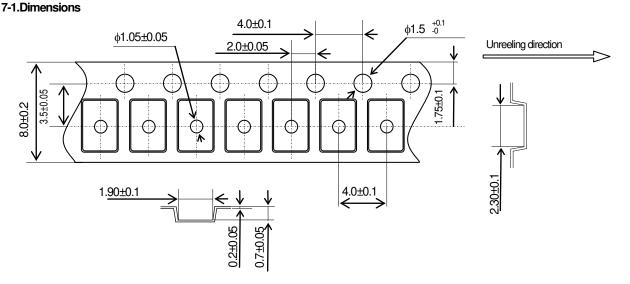
\*The font of marking is for reference only.

# 6. RECOMMENDED LAND PATTERN (not to scale)

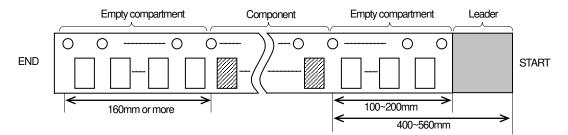




# 7. TAPING & REEL



#### 7-2.Leader and Carrier tape



7-3.Direction (Orientation shall be checked from the top cover tape side)

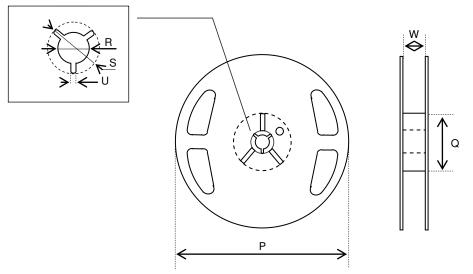


#### 7-4.Specification

- 1. Material of the carrier tape is either polystyrene or A-PET (ESD).
- 2. Material of the cover tape is polyester (ESD).
- 3. The seal tape shall not cover the sprocket holes and not protrude from the carrier tape.
- 4. Tensile strength of carrier tape: 10N or more.
- 5. The R of the corner of each cavity is 0.2RMAX.
- 6. The alignment between centers of the cavity and sprocket hole shall be 0.05mm or less.
- 7. The orientation shall be checked from the top cover tape side as shown in 7-3.
- 8. Peeling force of cover tape: 0.1 to 1.0N.
- 9. The component will fall out naturally when cover tape is removed and set upside down.

Cover tape 165°~180° Carrier tape E

### 7-5.Reel Specification



### 

| Symbol    | Р          | Q                  | R       |
|-----------|------------|--------------------|---------|
| Dimension | φ180 +0/-3 | φ <b>60 +1/-</b> 0 | φ13±0.2 |
| Symbol    | S          | U                  | W       |
| Dimension | φ21±0.8    | 2.0±0.5            | 9±1     |

(Unit: mm)

### 6330 Reel (15,000 pcs Max.)

| Symbol    | Р        | Q        | R       |
|-----------|----------|----------|---------|
| Dimension | φ330±2.0 | φ100±1.0 | φ13±0.2 |
| Symbol    | S        | U        | W       |
| Dimension | φ21±0.8  | 2.0±0.5  | 9.4±1.0 |

(Unit: mm)

# 8. Environmental requirements

After conducting the following tests, component needs to meet below conditions. Frequency: Fluctuation within +/-10 x  $10^{-6}$  CI: Fluctuation within +/-20% or 5 $\Omega$  whichever is larger

| 8.1 | Resistance to Shock     | Test condition<br>3 times natural drop from 100cm onto hard wooden board.  |  |  |
|-----|-------------------------|--|--|--|
| 8.2 | Resistance to Vibration | Test conditionfrequency: 10 - 55 - 10 HzAmplitude: 1.5mmCycle time: 15 minutesDirection: X,Y,Z (3direction),2h each.   |  |  |
| 8.3 | Resistance to Heat      | Test condition<br>The quartz crystal unit shall be stored at a<br>temperature of +85±2°C for 500h and subjected to<br>room temperature for 1h before measurement.  |  |  |
| 8.4 | Resistance to Cold      | Test condition<br>The quartz crystal unit shall be stored at a<br>temperature of -40±2°C for 500h and subjected to<br>room temperature for 1h before measurement.  |  |  |
| 8.5 | Thermal Shock           | Test conditionThe quartz crystal unit shall be subjected to 500 temperature<br>cycles shown in table below, Then it shall be subjected<br>to room temperature for 1h before mesurement.Cycle:-40±2°C (30min.) $\rightarrow$ +25±2°C(5min.)<br>$\rightarrow$ +85±2°C(30min.) $\rightarrow$ +25±2°C(5min.) |  |  |

| 8.6 | Resistance to Moisture | Test condition                                   |
|-----|------------------------|--|
|     |                        | The quartz crystal unit shall be stored at a     |
|     |                        | temperature of +60±2°C with relative humidity of |
|     |                        | 90% to 95% for 240 h. Then it shall be subjected |
|     |                        | to room temperature for 1h before measurement.   |
|     |                        |  |

8.7 Soldering condition 1.) Type of solder

Material  $\rightarrow$  lead free solder paste Melting point  $\rightarrow$  +220±5°C

2.) Reflow temp.profile

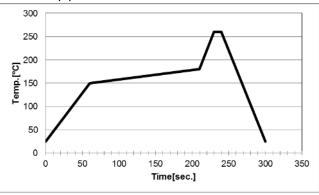
|            | Temp [°C]    | Time[sec]  |  |  |
|------------|--------------|------------|--|--|
| Preheating | +150 to +180 | 150 (typ.) |  |  |
| Peak       | +260±5       | 10 (max.)  |  |  |
| Total      | -            | 300 (max.) |  |  |

Frequency shift : ±2ppm

3.) Hand Soldering +350°C 3 sec max

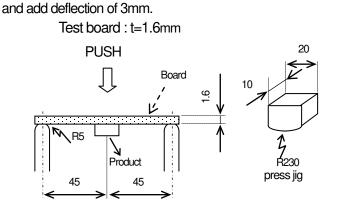
4.) Reflow Times 2 times in below Reflow temp. profile

Reflow temp.profile



8.8 Bending Strength

Solder this product in center of the circuit board (40mm X 100mm),



UNIT: mm

# 9. Cautions for use

(1) Soldering upon mounting

There is a possibility to influence product characteristics when Solder paste or conductive glue comes in contact with product lid or surface.

### (2) When using mounting machine

Please minimize the shock when using mounting machine to avoid any excess stress to the product.

### (3) Conformity of a circuit

We strongly recommend to make sure that Negative resistance (Gain) of IC is designed to be 3 times the ESR (Equivalent Series Resistance) of crystal unit.

# 10. Storage conditions

Please store product in below conditions, and use within 6 months. Temperature +18 to +30°C, and Humidity of 20 to 70 % in the packaging condition.

# 11. Manufacturing location

Kyocera Crystal Device Corporation Yamagata Plant Kyocera Crystal Device Corporation Shiga Yohkaichi Plant Kyocera Crystal Device (Thailand) Co., Ltd

# **12. Quality Assurance**

To be guaranteed by Kyocera Crystal Device Quality Assurance Division

### 13. Quality guarantee

In case when Kyocera Crystal Device Corporation rooted failure occurred within 1year after its delivery, substitute product will be arranged based on discussion. Quality guarantee of product after 1year of its delivery is waivered.

# 14. Others

In case of any questions or opinions regarding the Specification, please have it in written manner within 45 days after issued date.